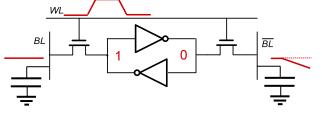


SRAM Operation

Read



SRAM read in non-destructive

- Reading the cell should not destroy the stored value

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Sizing SRAM Cell

- Read stability: Cell should not change value during read
 - $Q = 0: M_{5}, M_{1}$ both on
 - Voltage divider between M₅, M₁
 - $^{\bullet}$ $\rm V_{Q}$ should stay low, not to flip $\rm M_4\text{-}M_3$ inverter
 - $(W/L)_1 > (W/L)_5$
- Typically $(W/L)_1 = 1.5 (W/L)_5$
 - In finFETs: $(W/L)_1 = 2(W/L)_5$
- \bullet Read speed: Both M_5 and M_1

WL \overline{V}_{DD} $\overline{\mathsf{Q}}$ T M₅ M_1 BL \overline{BL}

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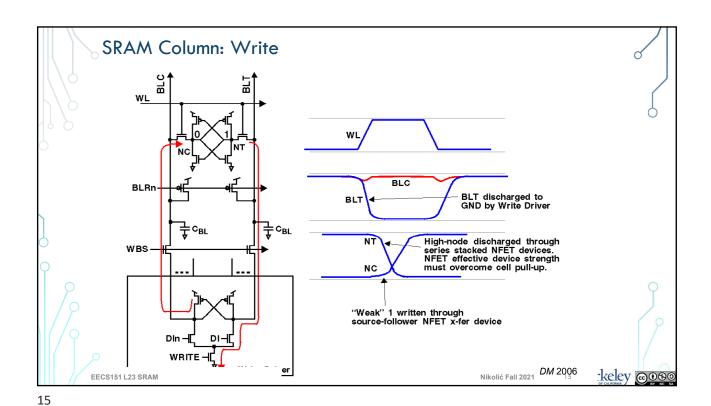
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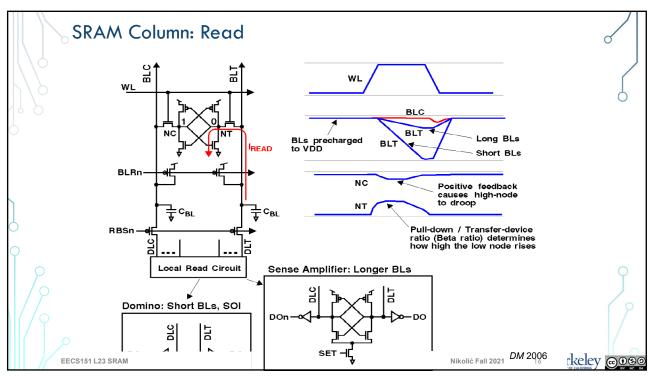
Sizing SRAM Cell

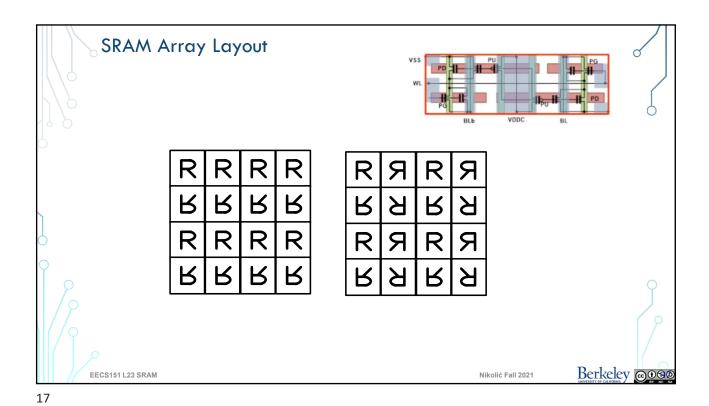
- Writeability: Cell should be writeable by pulling BL low
 - Q = 1, M_5 , M_2 both on
 - Voltage divider between M₅, M₂
 - $^{\bullet}$ $\rm V_{\rm Q}$ should pull below the switching point of M_4 - M_3 inverter
 - $(W/L)_5 > (W/L)_2$
- Typically $(W/L)_5 = (W/L)_2$ in planar
 - In finFETs: $(W/L)_5 = 2(W/L)_2$
 - 1:2:2 and 1:2:3 sizing

 V_{DD} M_2 M_4 $\rfloor M_5$ \overline{BL} BL 6T High-Current (HC) bitcell 0.049 um2 (1:2:2) Song, ISSCC'16 14 Berkeley 6000

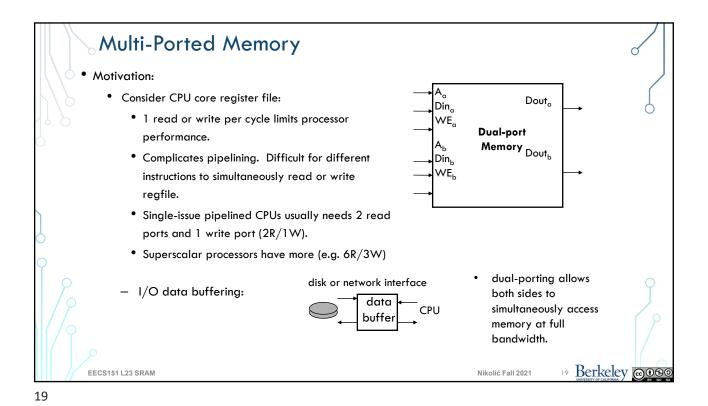
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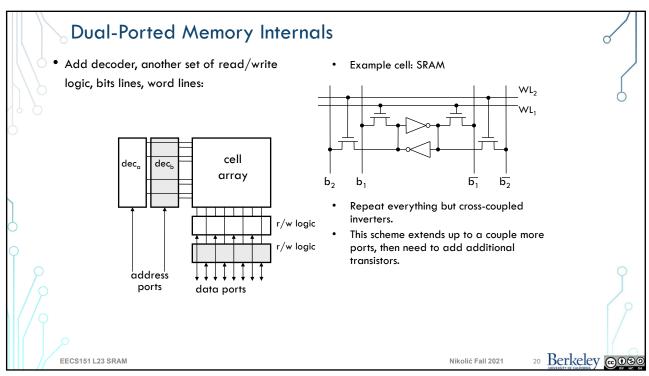


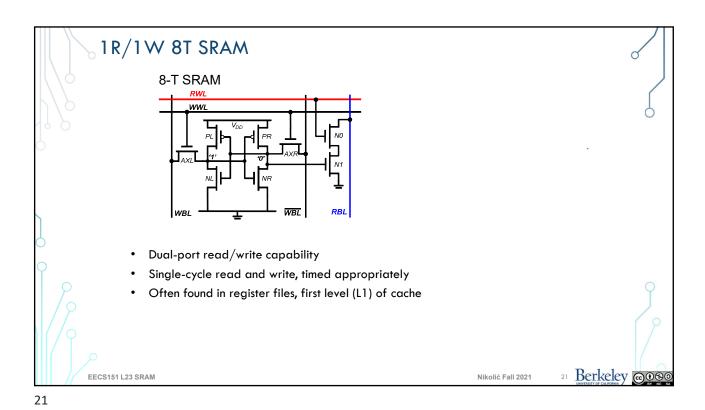


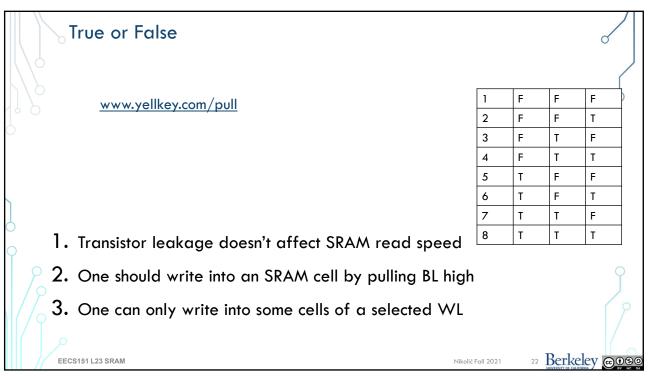


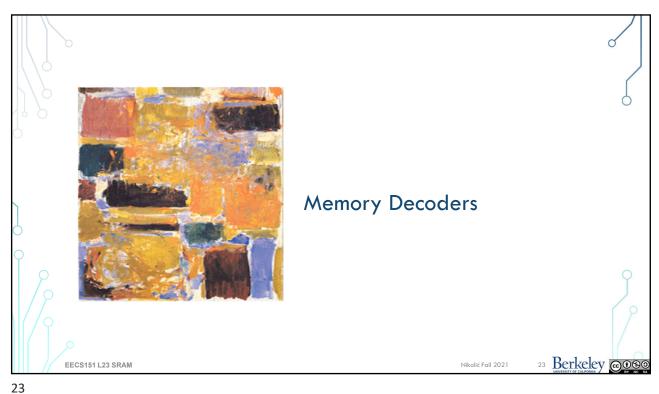
• Homework 10 posted on Friday, due 11/22
• No homework during Thanksgiving
• Project checkpoints #3 this week

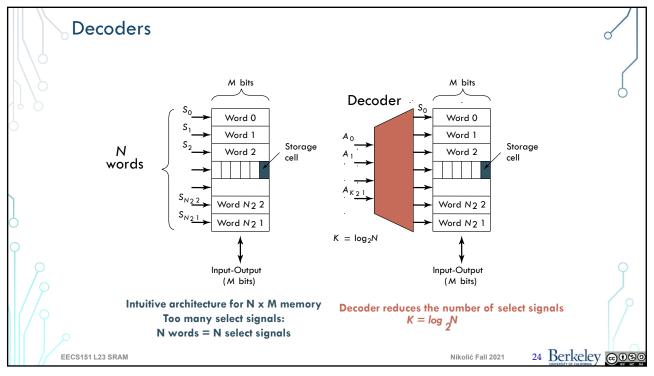


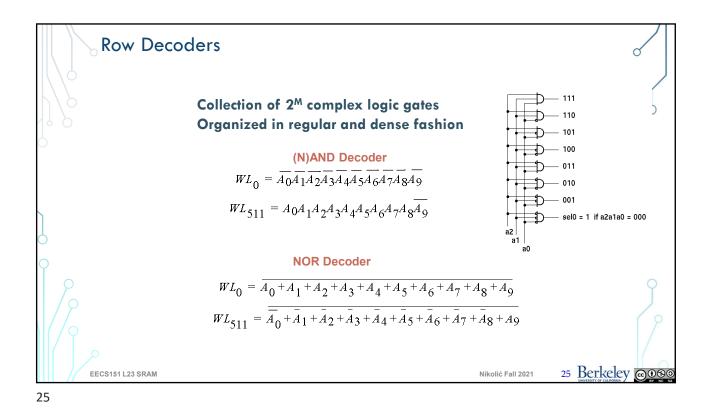


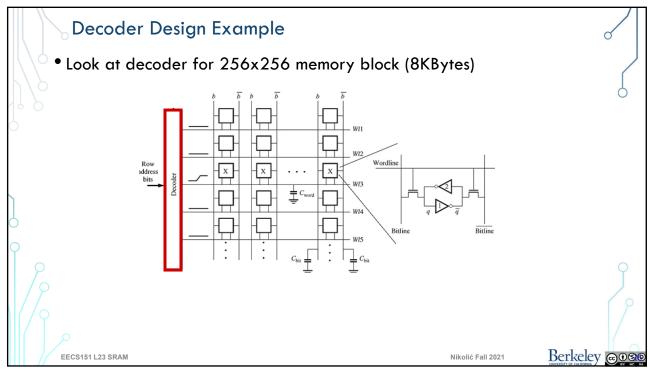


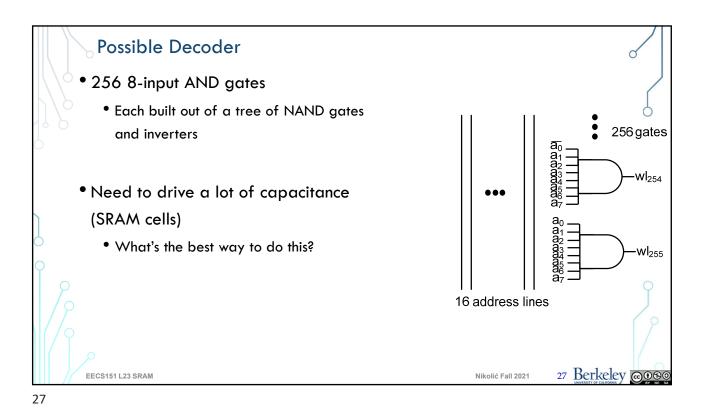


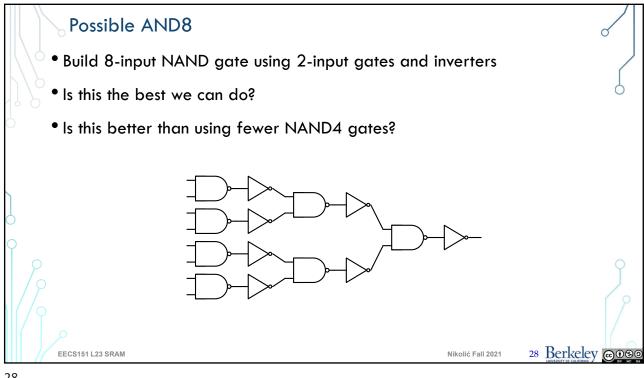








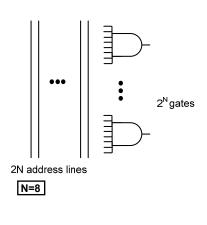






• Goal: Build fastest possible decoder with static CMOS logic

- What we know
 - Basically need 256 AND gates, each one of them drives one word line



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Problem Setup (1)

- Each wordline has 256 cells connected to it
- \bullet C_{WL} = 256*C_{cell} + C_{wire}
 - Ignore wire for now
- ullet Assume that decoder input capacitance is $C_{address} = 4 * C_{cell}$

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Problem Setup (2)

- ullet Each address bit drives $2^8/2$ AND gates
 - A0 drives $\frac{1}{2}$ of the gates, A0_b the other $\frac{1}{2}$ of the gates
- Total fanout on each address wire is:

$$F = \Pi B \frac{C_{load}}{C_{in}} = 128 \frac{\left(256C_{cell}\right)}{4C_{cell}} = 2^{7} \frac{\left(2^{8}C_{cell}\right)}{2^{2}C_{cell}} = 2^{13}$$

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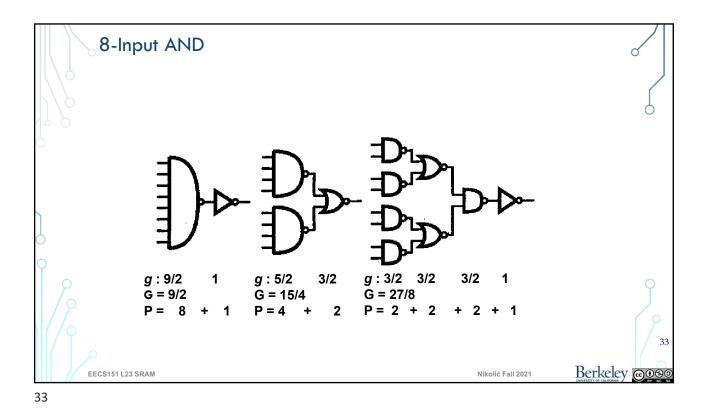
Decoder Fan-Out

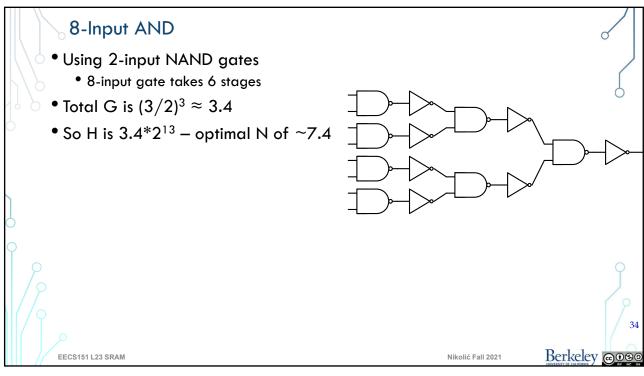
- F of 2^{13} means that we will want to use more than $\log_4(2^{13})=6.5$ stages to implement the AND8
- Need many stages anyways
 - So what is the best way to implement the AND gate?
 - Will see next that it's the one with the most stages and least complicated gates

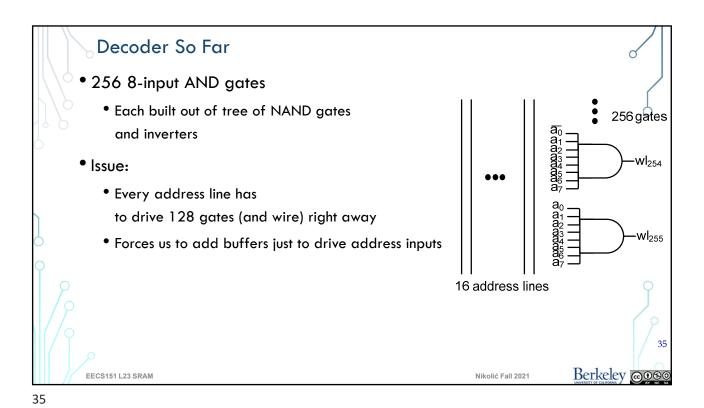
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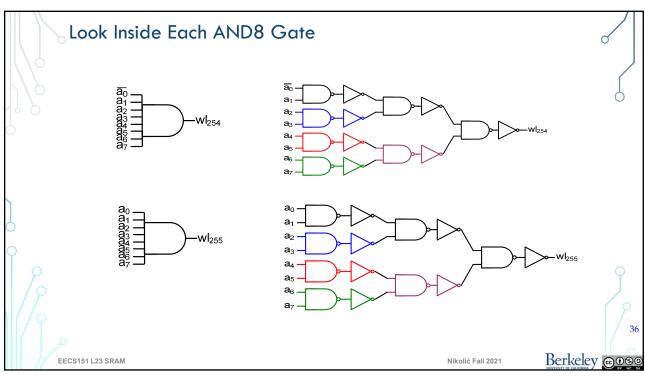
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Predecoders

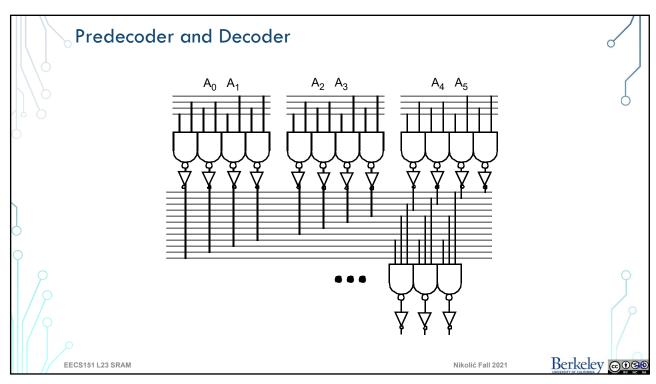
- Use a single gate for each of the shared terms
 - E.g., from A_0 , $\overline{A_0}$, A_1 , and $\overline{A_1}$, generate four signals: A_0A_1 , $\overline{A_0}A_1$, $A_0\overline{A_1}$, $\overline{A_0}\overline{A_1}$
- In other words, we are decoding smaller groups of address bits first
 - And using the "predecoded" outputs to do the rest of the decoding

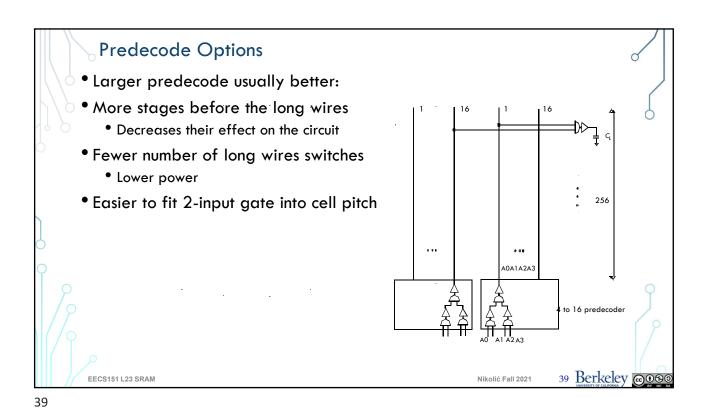
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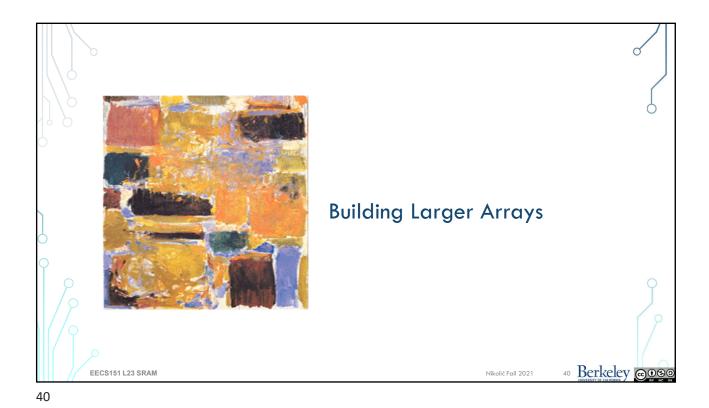
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	Building Larger Custom Arrays						
	4kB	Dec	4kB	4kB	Dec	4kB	• Each subarray is 2-8kB
	Col, I/O	Pre- Dec	Col, I/O	Col, I/O	Pre- Dec	Col, I/O	• Hierarchical decoding
Ó	4kB	Dec	4kB	4kB	Dec	4kB	• Peripheral overhead is 30-50%
	4kB	Dec	4kB	4kB	Dec	4kB	• Delay is wire dominated
	Col, I/O	Pre- Dec	Col, I/O	Col, I/O	Pre- Dec	Col, I/O	Scratchpads, caches, TLBs
φ	4kB	Dec	4kB	4kB	Dec	4kB	
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Cascading Memory-Blocks

How to make larger memory blocks out of smaller ones.

Increasing the width. Example: given 1Kx8, want 1Kx16

WE

Din[15:8]

Din[7:0]

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